Skyray Instruments



EDX 3600H

X-ray Fluorescence Spectrometer



EDX3600H

X-ray Fluorescence Spectrometer



EDX3600H X-Ray Fluorescence Spectrometer is an all-in-one XRF capable of virtually any elemental application. EDX3600H comes standard with best in class UHRD or SDD detector and advanced vacuum system and can be used for multiple testing types including Mineral, Alloy, RoHS, Plating Thickness and custom applications.

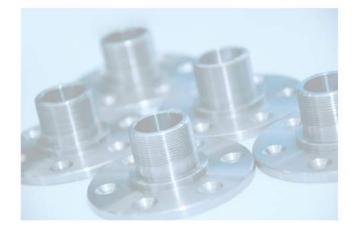
complete elemental analysis with EDX 3600H

Software Options

- Full-elemental analysis- Na-U
- RoHS/WEEE Analysis
- Mineral Analysis
- Alloy Analysis
- Plating Thickness
- Custom calibrations for virtually any application

Standard Configuration

- Efficient super-thin window x-ray light tube
- High-performance electronic cooling UHRD detector
- Signal-to-Noise Enhancer(SNE)
- CMOS HD camera
- Automatic Collimators and filters
- Triple X-Ray protection
- Vacuum Pump





EDX3600H X-ray Fluorescence Spectrometer



Technical Parameters

Power: 200W Ambient temperature: 15°C-30°C Sample chamber size: 320mmx100mm Weight: 65Kg

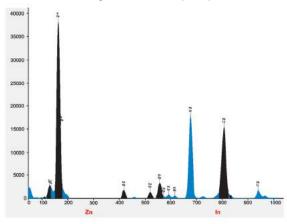
Voltage input: AC 220V (Optional: 110V) Ambient humidity: 35%-70% Instrument dimension: 660mmx510mmx350mm

Specifications

Measurable range: Na to U Analytical range: ppm-99.99% Simultaneous analysis: 20 plus elements Precision: 0.05% (content 96% T)

Testing time: 60s-200s Resolution: (140±5)eV Tube voltage: 5KV-50KV Tube current: 50 u A-1000 11 A

RoHS Analysis-Lead(Pb)





Name	Pb	Zn	Cu	Fe	Ca	Si	S	Mg	AI
1	53.62	5.05	3.56	10.11	1.19	3.98	14.16	0.28	0.27
2	53.45	4.95	3.48	9.91	1.28	3.37	15.30	0.32	0.26
3	53.32	5.15	3.49	9.89	1.32	3.54	15.23	0.20	0.26
4	53.84	5.13	3.29	9.94	1.26	3.46	14.98	0.35	0.24
5	53.42	5.07	3.88	9.69	1.25	3.37	15.36	0.61	0.25
6	53.79	5.09	3.46	10.10	1.24	4.12	15.48	0.29	0.28
7	53.23	5.04	3.48	9.97	1.28	3.84	14.98	0.44	0.26
8	53.31	5.06	3.64	9.66	1.19	3.21	14.65	0.52	0.24
9	53.80	5.13	3.54	9.76	1.34	3.94	14.32	0.42	0.27
10	53.19	5.01	3.31	9.82	1.27	4.16	15.04	0.37	0.26
11	52.86	5.34	3.67	9.24	1.60	3.72	14.16	0.43	0.29
Average value	53.44	5.09	3.53	9.83	1.29	3.70	14.88	0.38	0.26
Standard deviation	0.30	0.10	0.17	0.24	0.11	0.33	0.48	0.12	0.02
Relative standard deviation	0.57	1.96	4.68	2.48	8.64	8.90	3.25	30.37	5.87

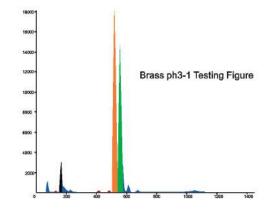
Repeatability



Skyray Instruments USA Inc X-Ray Fluorescence Spectrometers XRF Analyzers

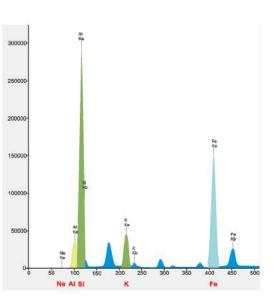
Alloy Analysis-Brass

Element	Cu	Pb	Fe	Sn	Ai	Ni	Mn	Si
Content	58.6531	3.0070	0.3866	0.0002	0.2287	0.2297	0.0002	0.0019
Element	Sb	Co	Р	S	Zn	Bi	Cr	
Content	0.0002	0.0008	0.0098	0.0005	37.0130	0.3411	0.0052	



Analysis-Kaolin (Zn)

Name	Na2O	AI203	SIO2	Fe2O3	K20
Kaolin-1	0.4775	16.3222	74.6662	4.8268	3.4161
Kaolin-2	0.5892	16.5028	74.6302	4.8413	3.4483
Kaolin-3	0.4711	16.4921	74.6794	4.8281	3.4532
Kaolin-4	0.5814	16.4986	74.6796	4.8460	3.4576
Kaolin-5	0.5375	16.4457	74.6653	4.8253	3.4422
Kaolin-6	0.5425	16.4979	74.6883	4.8258	3.4540
Kaolin-7	0.5494	16.4726	74.6485	4.8116	3.4443
Kaolin-8	0.4972	16.4997	74.7446	4.8327	3.444
Kaolin-9	0.5439	16.5299	74.6029	4.8235	3.439
Kaolin-10	0.4972	16.4562	74.6771	4.8126	3.438
Kaolin-11	0.5773	16.5287	74.7196	4.8233	3.447
Average value	0.5331	16.4769	74.6729	4.8270	3.444
Range	0.1181	0.2076	0.1416	0.0343	0.040
Standard deviation	0.0418	0.0576	0.0388	0.0104	0.0110
Relative standard deviation	7,8326	0.3495	0.0520	0.2147	0.320



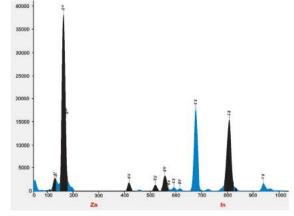
Mineral Analysis-Zinc (Zn)



Repeatability

Name	Pb	Zn	Cu	Fe	Ca	Si	S	Mg	AI
1	53.62	5.05	3.56	10.11	1.19	3.98	14.16	0.28	0.27
2	53.45	4.95	3.48	9.91	1.28	3.37	15.30	0.32	0.26
3	53.32	5.15	3.49	9.89	1.32	3.54	15.23	0.20	0.26
4	53.84	5.13	3.29	9.94	1.26	3.46	14.98	0.35	0.24
5	53.42	5.07	3.88	9.69	1.25	3.37	15.36	0.61	0.25
6	53.79	5.09	3.46	10.10	1.24	4.12	15.48	0.29	0.28
7	53.23	5.04	3.48	9.97	1.28	3.84	14.98	0.44	0.26
8	53.31	5.06	3.64	9.66	1.19	3.21	14.65	0.52	0.24
9	53.80	5.13	3.54	9.76	1.34	3.94	14.32	0.42	0.27
10	53.19	5.01	3.31	9.82	1.27	4.16	15.04	0.37	0.26
11	52.86	5.34	3.67	9.24	1.60	3.72	14.16	0.43	0.29
Average value	53.44	5.09	3.53	9.83	1.29	3.70	14.88	0.38	0.26
Standard deviation	0.30	0.10	0.17	0.24	0.11	0.33	0.48	0.12	0.02
Relative standard deviation	0.57	1.96	4.68	2.48	8.64	8.90	3.25	30.37	5.87











Skyray Instruments USA, Inc 1717 N. Akard Street, Ste 2520 Dallas, Texas, 75201 USA

Spectroscopy

Chromatography Mass Spectrometry

www.skyray-instruments.net Sales@skyray-instruments.net

+ 1 972 638 9035

Skyray Instruments specializes in the R&D, manufacturing and sales of analytical and measuring instruments in Spectroscopy, Chromatography and Mass Spectroscopy fields. Our Products include X-ray Fluorescence Spectrometry, Atomic Absorption Spectrometry, Gas Chromatography, Inductively Coupled Plasma Spectrometry, Mass Spectrometry and many others

Skyray has been providing customers around the world with reliable and affordable Scientific Instruments for more than 20 years

Product description and specifications in this document are subject to change without notice. Copying, distributing or any use of material contained in this document for any commercial purpose without permission from Skyray Instruments USA, Inc is prohibited. Printed in USA